

<b>Notice of References Cited</b>	Application/Control No. 10/735,912	Applicant(s)/Patent Under Reexamination CHOI, SEUNG-CHUL	
	Examiner Jeffrie R. Lund	Art Unit 1763	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,903,711	05-1999	Okase, Wataru	392/418
*	B	US-6,294,026 B1	09-2001	Roithner et al.	118/715
*	C	US-7,175,713 B2	02-2007	Thakur et al.	118/715
*	D	US-2001/0047759 A1	12-2001	Matsui et al.	118/723.00E
*	E	US-2003/0000473 A1	01-2003	Chae et al.	118/715
*	F	US-2003/0037802 A1	02-2003	Nakahara et al.	134/1.1
*	G	US-2003/0203626 A1	10-2003	Derderian et al.	438/689
*	H	US-2004/0112539 A1	06-2004	Larson et al.	156/345.33
*	I	US-2004/0112540 A1	06-2004	Larson et al.	156/345.33
*	J	US-2004/0123806 A1	07-2004	Choi, Seung-Chul	118/729
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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